



<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)	Atty Docket No.	Application No.:
	UNTYP027	10/665,882
	Applicant:	
	RINERSON et al.	
Filing Date	September 19, 2003	Group
		2811

#### U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
JH	A1	6,204,139	3/2001	Liu et al.	438	305	

#### Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	B1							

#### Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
JH	C1	Baikalov et al., "Field-Driven Hysteric and Reversible Resistive Switch at the Ag Pro <sub>0.7</sub> Ca <sub>0.3</sub> MnO <sub>3</sub> Interface", May 2003, Department of Physics and Texas Center for Superconductivity, University of Houston, pp. 1-8.
JH	C2	Beck et al., "Reproducible switching effect in thin oxide films for memory applications", July 2000, Applied Physics Letters, Vol. 77, No. 1, pp. 139-141.
JH	C3	Gerstner et al., "Nonvolatile memory effects in nitrogen doped tetrahedral amorphous carbon thin films," November 1998, Journal of Applied Physics, Vol. 84, No. 10, pp. 5647-5651.
JH	C4	Mieville et al., "Transport across conducting ferromagnetic oxide/metal interfaces", September 1998, Applied Physics Letters, Vol. 73, No. 12, pp. 1736-1738.
JH	C5	Liu et al., "A New Concept for Non-Volatile Memory: The Electric-Pulse Induced Resistive Change Effect in Colossal Magnetoresistive Thin Films", University of Houston, pp. 1-7.
JH	C6	Liu et al., "Electric-pulse-induced reversible resistance change effect in magnetoresistive films", May 2000, Applied Physics Letters, Vol. 76, No. 19, pp. 2749-2751.
JH	C7	Plecken et al., "Degradation of LaMnO <sub>3-y</sub> surface layer in LaMnO <sub>3-y</sub> /metal interface", July 2002, Applied Physics Letters, Vol. 81, No. 5, pp. 859-861.
JH	C8	Rossel et al., "Electrical current distribution across a metal-insulator-metal structure during bistable switching", September 2001, Journal of Applied Physics, Vol. 90, No. 6, pp. 2892-2898.

9/29	C9	Simmons et al., "New conduction and reversible memory phenomena in thin insulating films", 1967, Proc. Roy. Soc. A., Vol. 301, pp. 77-102.
9/29	C10	Tulina et al., "Reproducible switching in normal metal-manganite single crystal point contacts with memory effect", 2003, Physica C., Vol. 385, pp. 563-567.
9/29	C11	Tulina et al., "Reversible electrical switching at the $\text{Bi}_2\text{Sr}_2\text{CaCu}_2\text{O}_{8+y}$ surface in the normal metal - $\text{Bi}_2\text{Sr}_2\text{CaCu}_2\text{O}_{8+y}$ single crystal heterojunction," 2001, Physica C., Vol. 366, pp. 23-30.
9/29	C12	Watanabe et al., "Current-driver insulator-conductor transition and nonvolatile memory in chromium-doped $\text{SrTiO}_3$ single crystals," June 2001, Applied Physics Letters, Vol. 78, No. 23, pp. 3738-3740.
9/29	C13	Ziese et al., "Voltage-controlled colossal magnetoresistance in manganite/normal-metal heterostructures", February 1998, Physical Review B, Vol. 57, No. 5, pp. 2963-2966.
Examiner		Date Considered
JSC/Ehert		9/29/04

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.